



ALPHA & OMEGA
SEMICONDUCTOR

AO8810

20V Common-Drain Dual N-Channel MOSFET

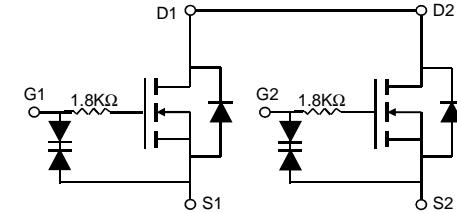
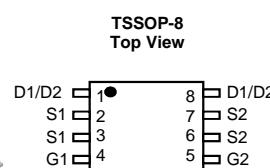
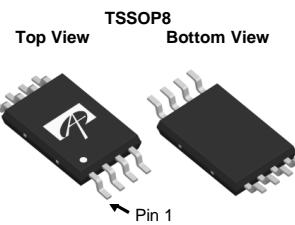
General Description

The AO8810 uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge. It is ESD protected. This device is suitable for use as a uni-directional or bi-directional load switch, facilitated by its common-drain configuration.

Product Summary

V_{DS}	20V
I_D (at $V_{GS}=4.5V$)	7A
$R_{DS(ON)}$ (at $V_{GS}= 4.5V$)	< 20mΩ
$R_{DS(ON)}$ (at $V_{GS} = 4.0V$)	< 20.5mΩ
$R_{DS(ON)}$ (at $V_{GS} = 3.1V$)	< 21.5mΩ
$R_{DS(ON)}$ (at $V_{GS} = 2.5V$)	< 23mΩ
$R_{DS(ON)}$ (at $V_{GS} = 1.8V$)	< 28mΩ

ESD protected



Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	20	V
Gate-Source Voltage	V_{GS}	± 8	V
Continuous Drain Current	I_D	7	A
Current $T_A=70^\circ\text{C}$		5.7	
Pulsed Drain Current ^C	I_{DM}	25	
Power Dissipation ^B	P_D	1.5	W
$T_A=70^\circ\text{C}$		1.0	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A $t \leq 10\text{s}$	$R_{\theta JA}$	64	83	°C/W
Maximum Junction-to-Ambient ^{A,D} Steady-State		89	120	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	53	70	°C/W



Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	20			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=20\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 8\text{V}$			± 10	μA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.4	0.7	1.1	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	25			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=4.5\text{V}, I_D=7\text{A}$ $T_J=125^\circ\text{C}$		16 22	20 30	$\text{m}\Omega$
		$V_{GS}=4.0\text{V}, I_D=7\text{A}$			16.2	$\text{m}\Omega$
		$V_{GS}=3.1\text{V}, I_D=6.5\text{A}$			17	$\text{m}\Omega$
		$V_{GS}=2.5\text{V}, I_D=6.5\text{A}$			18	$\text{m}\Omega$
		$V_{GS}=1.8\text{V}, I_D=5\text{A}$			21	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=7\text{A}$		50		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.62	1	V
I_S	Maximum Body-Diode Continuous Current				2	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=10\text{V}, f=1\text{MHz}$		1295		pF
C_{oss}	Output Capacitance			160		pF
C_{rss}	Reverse Transfer Capacitance			87		pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		1.8		$\text{K}\Omega$
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=10\text{V}, I_D=7\text{A}$		10	14	nC
Q_{gs}	Gate Source Charge			4.2		nC
Q_{gd}	Gate Drain Charge			2.6		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=4.5\text{V}, V_{DS}=10\text{V}, R_L=1.54\Omega, R_{\text{GEN}}=3\Omega$		280		ns
t_r	Turn-On Rise Time			328		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			3.76		us
t_f	Turn-Off Fall Time			2.24		us
t_{rr}	Body Diode Reverse Recovery Time	$I_F=7\text{A}, dI/dt=100\text{A}/\mu\text{s}, V_{GS}=-9\text{V}$		31		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=7\text{A}, dI/dt=100\text{A}/\mu\text{s}, V_{GS}=-9\text{V}$		6.8		nC

A. The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{ C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{ C}$, using $\leqslant 10\text{s}$ junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{ C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{ C}$.

D. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to lead $R_{\theta JL}$ and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{ C}$. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

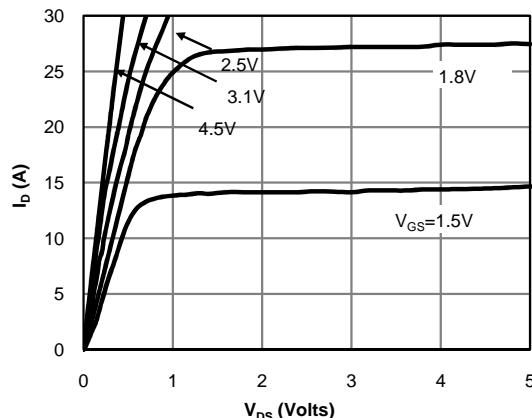


Fig 1: On-Region Characteristics (Note E)

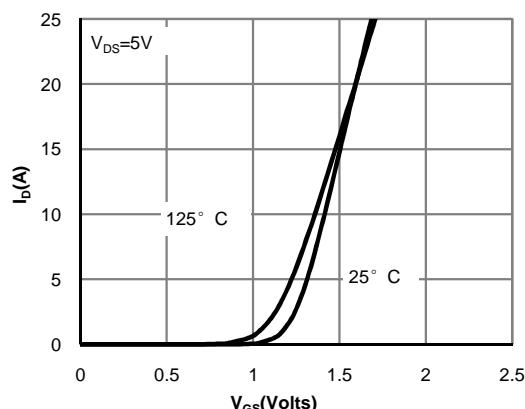


Figure 2: Transfer Characteristics (Note E)

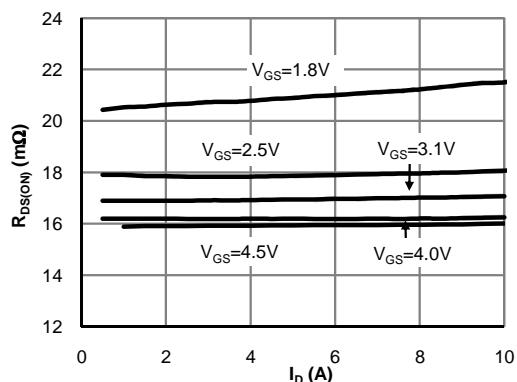


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

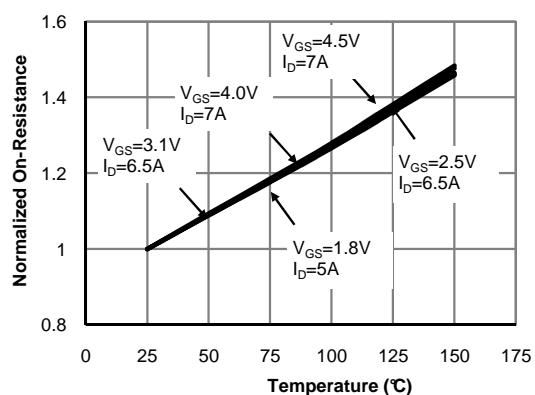


Figure 4: On-Resistance vs. Junction Temperature (Note E)

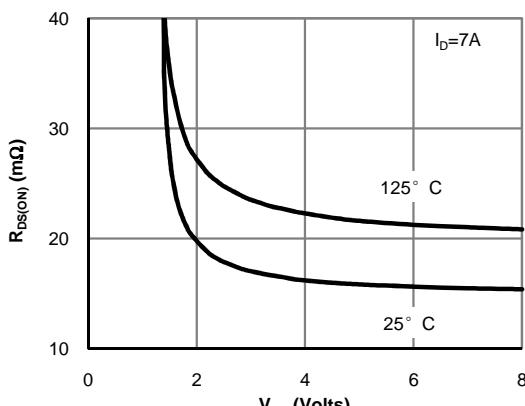


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

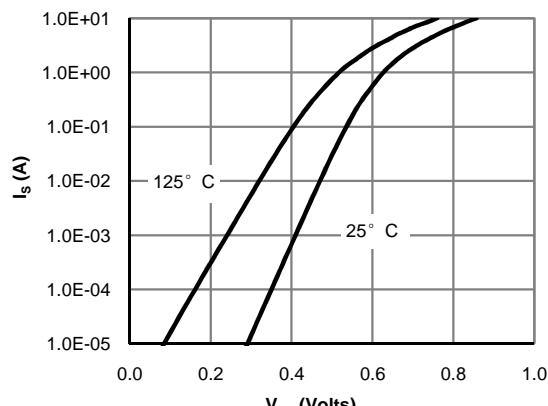


Figure 6: Body-Diode Characteristics (Note E)



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

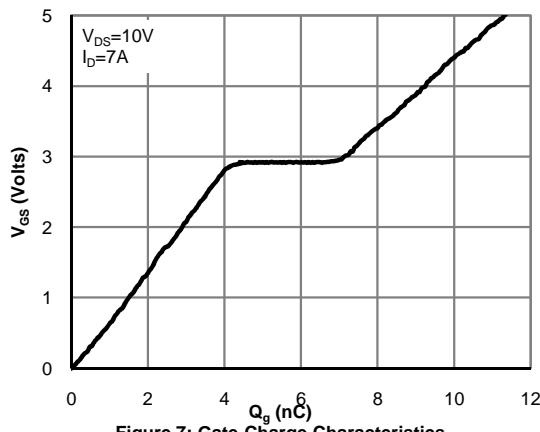


Figure 7: Gate-Charge Characteristics

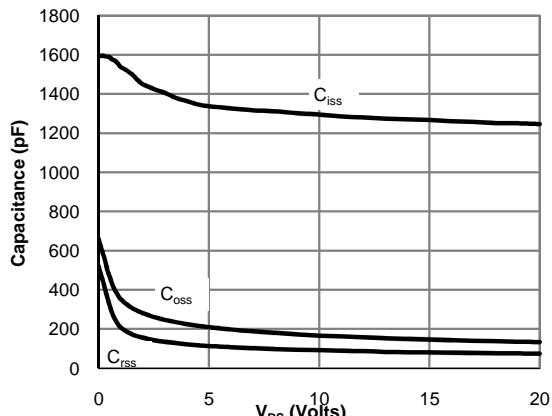


Figure 8: Capacitance Characteristics

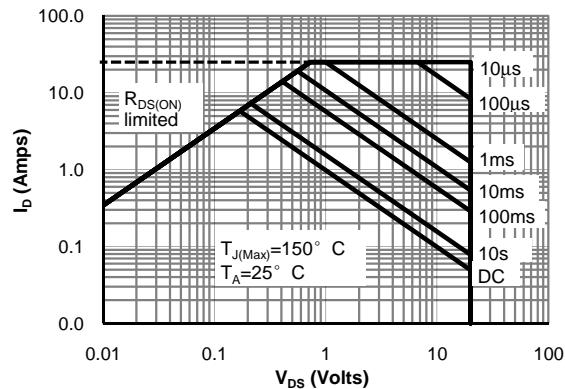


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

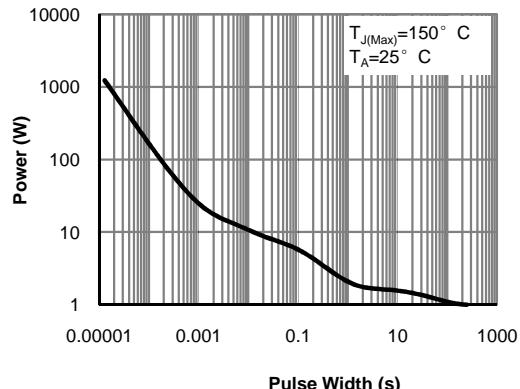


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

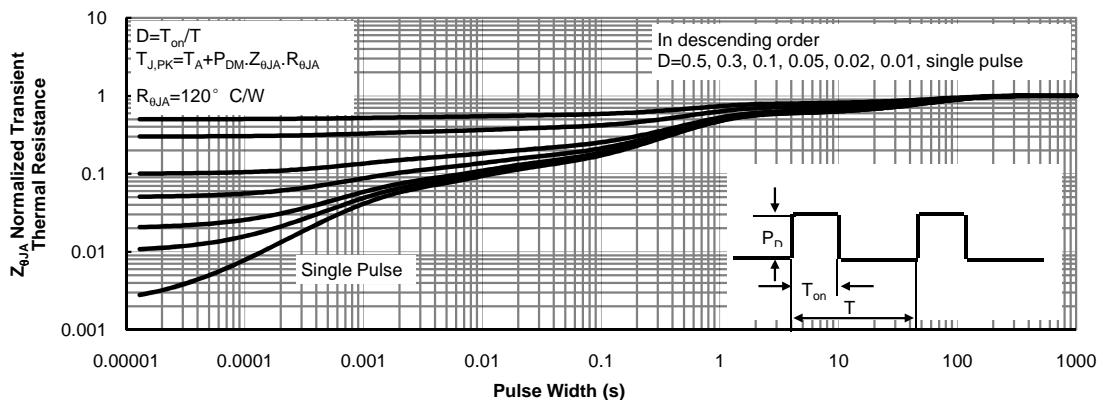
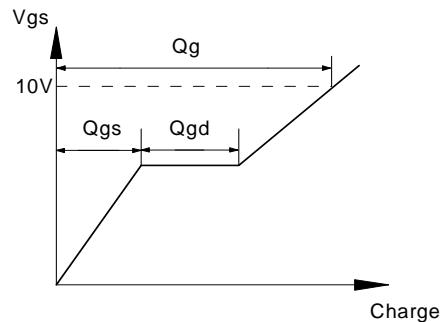
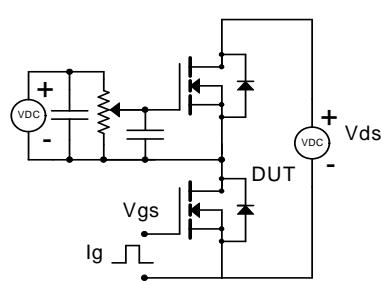


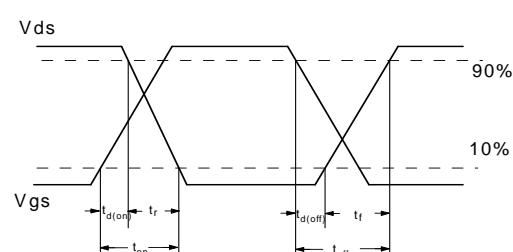
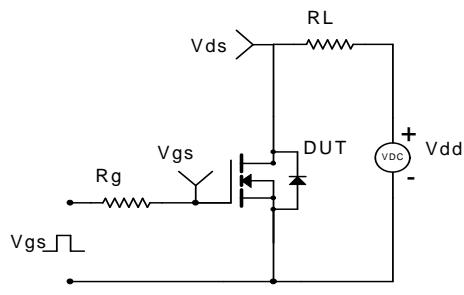
Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)



Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

